

HM2384DR

N-Channel Enhancement Mode MOSFET

➤ Features

VDS	VGS	RDSON Typ.	ID
20V	±12V	11mR@10V	8A
		13mR@4V5	
		16mR@2V5	

➤ Description

Advance trench process technology.

High density cell design for ultralow on-resistance.

High power and current handling capability.

Fully characterized avalanche voltage and current.

➤ Applications

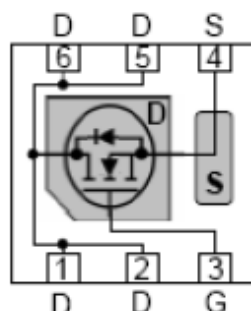
- Load Switch
- Li-ion battery protection

➤ Ordering Information

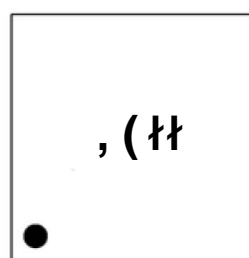
Device	Package	Shipping
HM2384DR	DFN2x2	3000/Reel

➤ Pin configuration

Top view



Bottom View



Marking

➤ **Absolute Maximum Ratings**($T_A=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V_{DSS}	Drain-to-Source Voltage	20	V
V_{GSS}	Gate-to-Source Voltage	± 12	V
I_D	Continuous Drain Current ^a	8	A
I_{DM}	Pulsed Drain Current ^b	30	A
P_D	Power Dissipation ^c	3.8	W
P_{DSM}	Power Dissipation ^a	1.8	W
T_J	Operation junction temperature	-25 to 85	$^{\circ}\text{C}$
T_{STG}	Storage temperature range	-55 to 150	$^{\circ}\text{C}$

➤ **Thermal Resistance Ratings**($T_A=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Typical	Maximum	Unit
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance ^a		75	$^{\circ}\text{C}/\text{W}$
$R_{\theta JC}$	Junction-to-Case Thermal Resistance		35	

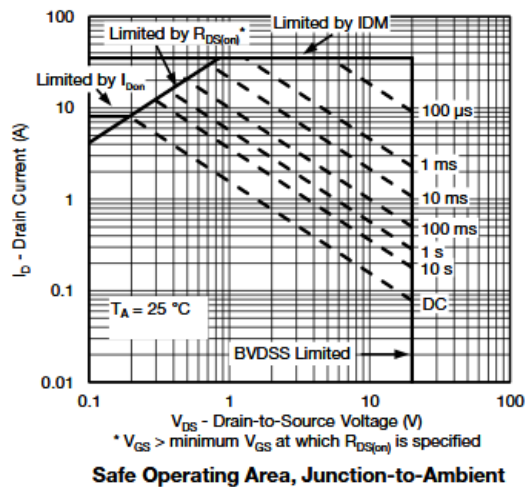
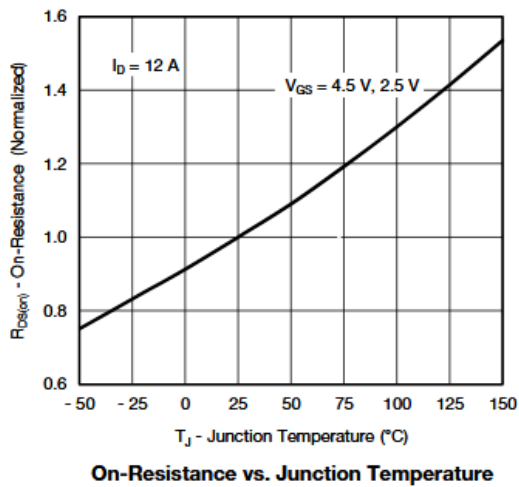
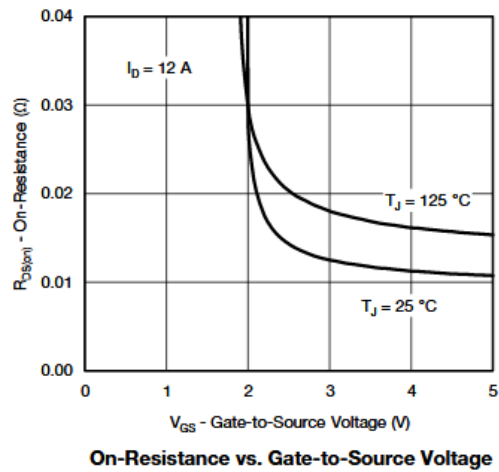
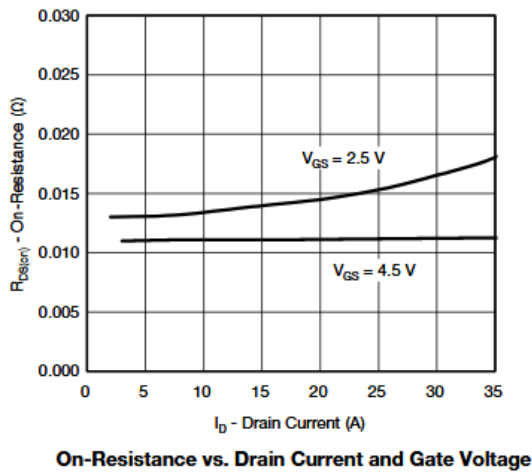
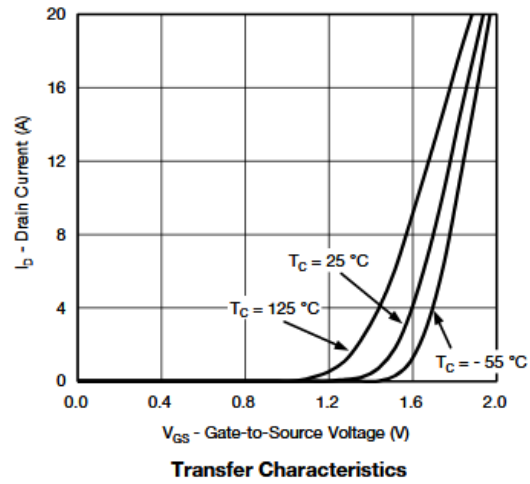
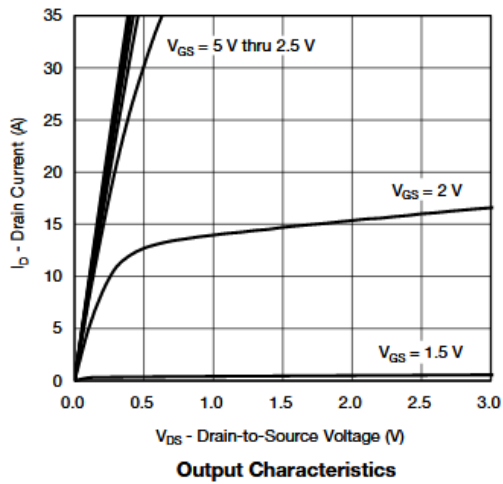
Note:

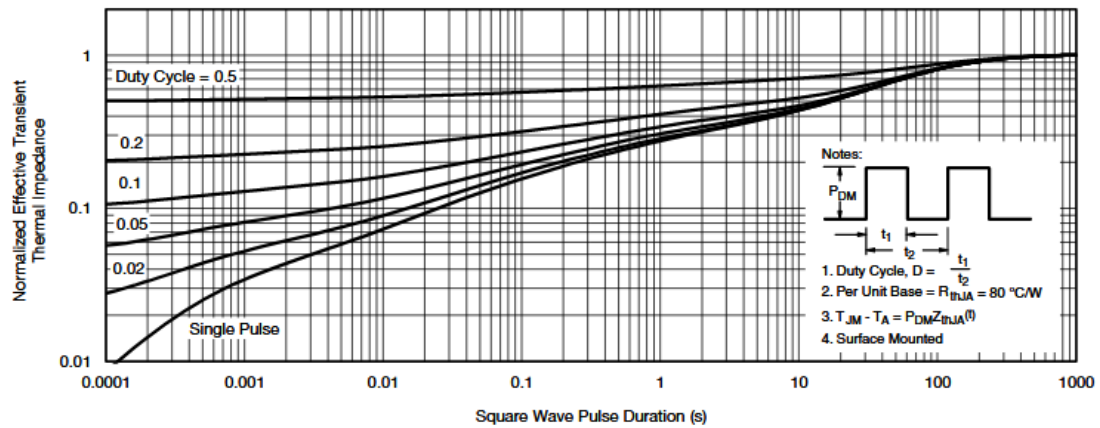
- The value of $R_{\theta JA}$ is measured with the device mounted on 1 in² FR-4 board with 2oz.copper,in a still air environment with $T_A=25^{\circ}\text{C}$.The value in any given application depends on the user is specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.
- Repetitive rating, pulse width limited by junction temperature.
- The power dissipation P_D is based on $T_{J(MAX)}=150^{\circ}\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heat sinking is used.

➤ **Electronics Characteristics**($T_A=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ.	Max	Unit
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	0.7	1	V
$R_{DS(on)}$	Drain-Source On- Resistance	$V_{GS}=10V, I_D=4.5A$		11	12	mR
		$V_{GS}=4.5V, I_D=3.5A$		13	15	
		$V_{GS}=2.5V, I_D=2.5A$		16	18	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=16V, V_{GS}=0V$			1	μA
I_{GSS}	Gate-Source leak current	$V_{GS}=\pm 12V, V_{DS}=0V$			± 100	nA
G_{FS}	Transconductance	$V_{DS}=5V, I_D=4.5A$		10		S
V_{SD}	Forward Voltage	$V_{GS}=0V, I_S=0.5A$		0.8	1.3	V
C_{iss}	Input Capacitance	$V_{DS}=10V, V_{GS}=0V,$ $f=1MHz$		600		pF
C_{oss}	Output Capacitance			330		
C_{rss}	Reverse Transfer Capacitance			140		
$T_{D(ON)}$	Turn-on delay time	$V_{GEN}=4.5V, R_L=10R,$ $V_{DS}=10V, R_G=6R, I_D=1A$		7		ns
T_r	Rise Time			13		
$T_{D(OFF)}$	Turn-off delay time			48		
T_f	Fall Time			22		
Q_g	Total Gate charge	$V_{GS}=4.5V, V_{DS}=10V,$ $I_D=4A$		8.5		nC
Q_{gs}	Gate to Source charge			1.8		
Q_{gd}	Gate to Drain charge			2.2		

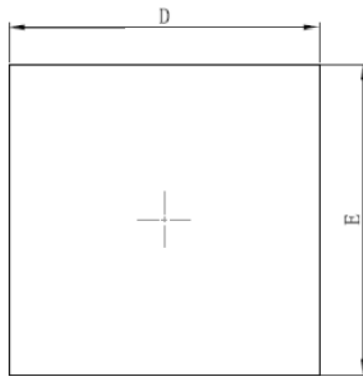
➤ Typical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)



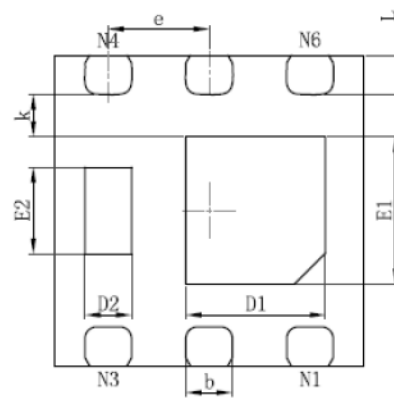


Normalized Thermal Transient Impedance, Junction-to-Ambient

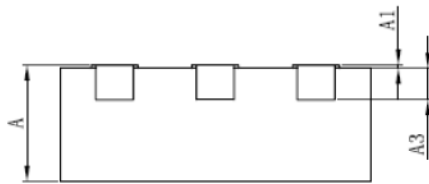
➤ Package Information



TOP VIEW



BOTTOM VIEW



SIDE VIEW

DFN2x2-6L

Symbol	Dimensions In Millimeters	
	Min.	Max.
A	0.700	0.800
A1	0.000	0.050
A3	0.203REF.	
D	1.924	2.076
E	1.924	2.076
D1	0.800	1.000
E1	0.850	1.050
D2	0.200	0.400
E2	0.460	0.660
k	0.200MIN.	
b	0.250	0.350
e	0.650TYP.	
L	0.174	0.326